FAIRCHILD

FDS6689S

30V N-Channel PowerTrench[®] SyncFET[™]

General Description

The FDS6689S is designed to replace a single SO-8 MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{DS(ON)}$ and low gate charge. The FDS6688S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

Applications

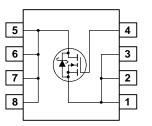
www.DataSheei4U.com • Synchronous Rectifier for DC/DC converter –

- Notebook Vcore low side switch
 - Point of Load low side switch



Features

- 16 A, 30 V. $\begin{array}{l} R_{DS(ON)} = 5.4 \ m\Omega \ @ \ V_{GS} = 10 \ V \\ R_{DS(ON)} = 6.5 \ m\Omega \ @ \ V_{GS} = 4.5 \ V \end{array}$
- Includes SyncFET Schottky body diode
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$ and fast switching
- High power and current handling capability
- 100% R_G (Gate Resistance) tested

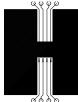


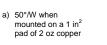
Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol		Parameter	Ratings	Units	
V _{DSS}	Drain-Source	Voltage		30	V
V _{GSS}	Gate-Source	Voltage		±20	V
D	Drain Current	t – Continuous	(Note 1a)	16	A
		- Pulsed		50	
P _D	Power Dissipation for Single Operation (Note 1a) (Note 1b)			2.5	W
				1.2	
			(Note 1c)	1	
T _J , T _{STG}	Operating an	d Storage Junction Te	mperature Range	-55 to +125	°C
Therma _{Rөја}	Thermal Res	eristics istance, Junction-to-A	mbient (Note 1a)	50	°C/W
R _{eJC}	Thermal Resi	stance, Junction-to-C	ase (Note 1)	25	
Packag	e Marking	and Ordering	Information		
Device Marking		Device	Reel Size	Tape width	Quantity
FDS6689S		FDS6689S	13"	12mm	2500 units

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Electrical Characteristics $T_{A} = 25^{\circ}C$ unless otherwise noted Symbol Min Max Units Parameter Test Conditions Тур **Off Characteristics** $\mathsf{BV}_{\mathsf{DSS}}$ Drain-Source Breakdown Voltage $V_{GS} = 0 V$, $I_D = 1 \text{ mA}$ 30 V Breakdown Voltage Temperature $I_D = 1$ mA, Referenced to $25^{\circ}C$ mV/°C ΔBV_{DSS} 28 Coefficient $\Delta T_{\rm J}$ Zero Gate Voltage Drain Current $V_{DS} = 24 V$, $V_{GS} = 0 V$ 500 I_{DSS} μΑ $V_{GS} = \pm 20 V$, Gate-Body Leakage $V_{DS} = 0 V$ ±100 I_{GSS} nA **On Characteristics** $I_D = 1 \text{ mA}$ Gate Threshold Voltage V $V_{DS} = V_{GS}$, 1.6 V_{GS(th)} 1 3 $\Delta V_{GS(th)}$ Gate Threshold Voltage $I_D = 1$ mA, Referenced to $25^{\circ}C$ mV/°C -4 **Temperature Coefficient** ΔT_{J} $I_{D} = 16 \text{ A}$ $V_{GS} = 10 V$, R_{DS(on)} Static Drain-Source 4.5 5.4 mΩ **On-Resistance** $V_{GS} = 4.5 V$, $I_{D} = 14.5 \text{ A}$ 5.2 6.5 V_{GS}=10 V, I_D =16 A, T_J=125°C 6.1 www.DataSheet4U.grom $V_{DS} = 10 V,$ $I_{D} = 16 \text{ A}$ 74 Forward Transconductance S **Dynamic Characteristics** 3290 pF Ciss Input Capacitance $V_{DS} = 15 V$, $V_{GS} = 0 V$, Coss **Output Capacitance** f = 1.0 MHz 890 pF Crss **Reverse Transfer Capacitance** 290 pF R_{G} Gate Resistance $V_{GS} = 15 \text{ mV},$ f = 1.0 MHz 1.5 2.6 Ω Switching Characteristics (Note 2) Turn-On Delay Time 12 22 $V_{DD} = 15 V$, $I_{D} = 1 A$, t_{d(on)} ns $V_{GS} = 10 V$, $R_{GEN} = 6 \ \Omega$ Turn-On Rise Time 12 22 tr ns $t_{\text{d(off)}}$ Turn-Off Delay Time 30 46 ns Turn-Off Fall Time t_f 60 96 ns Q_{g(TOT)} Total Gate Charge at V_{GS}=10V 56 78 nC $V_{DS} = 15 V$, $I_{D} = 16 \text{ A}$ Q_{g} Total Gate Charge at V_{GS}=5V 31 44 nC Q_{gs} Gate-Source Charge 8.2 nC Q_{gd} Gate-Drain Charge 9.0 nC **Drain–Source Diode Characteristics and Maximum Ratings** Drain–Source Diode Forward V_{SD} $V_{GS} = 0 V$, $I_S = 3.5 A$ (Note 2) 380 700 m٧ Voltage **Diode Reverse Recovery Time** $I_{\rm F} = 16 \, \rm A,$ 30 trr ns $d_{iF}/d_{t} = 300 \text{ A/}\mu\text{s}$ (Note 3) Diode Reverse Recovery Current 2 I_{RM} А Qrr Diode Reverse Recovery Charge 31 nC Notes: 1. R_{0,JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design. αφφρ





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b) 105°/W when mounted on a .04 in² pad of 2 oz copper

c) 125°/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

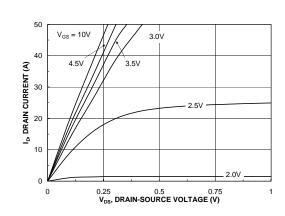
2. Pulse Test: Pulse Width < 300 µs, Duty Cycle < 2.0%.

3. See "SyncFET Schottky body diode characteristics" below.

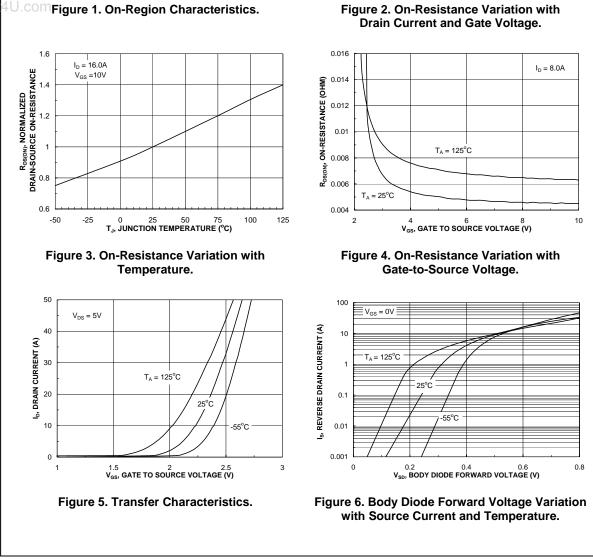
FDS6689S Rev B (W)

FDS6689S

Typical Characteristics







2.6

2.4

0.8

0

V_{GS} = 2.5V

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10

3.5V

4.0V

20 30 I_D, DRAIN CURRENT (A)

- 6.0V

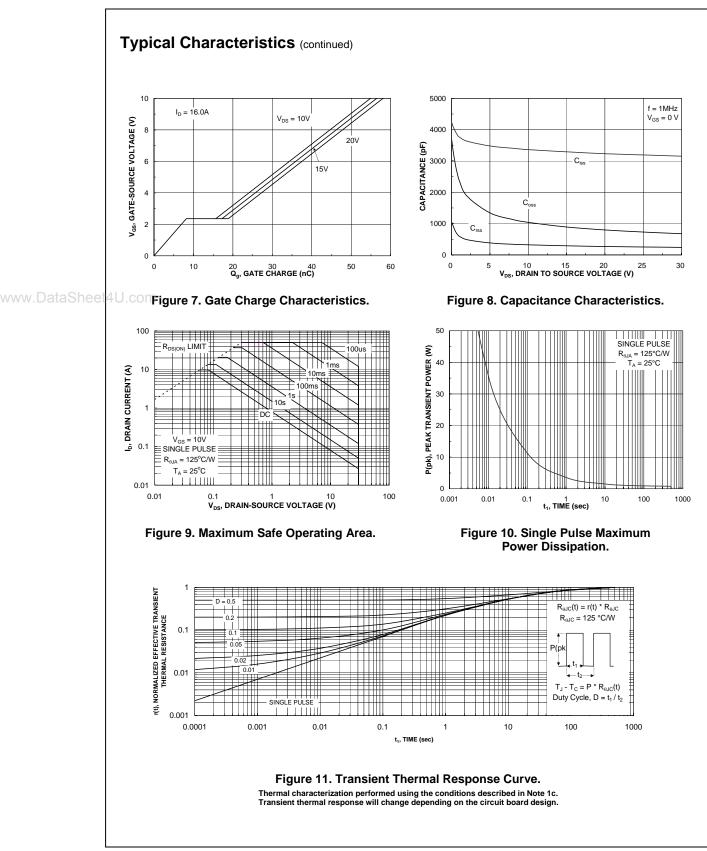
40

10V

50

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Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6689S.

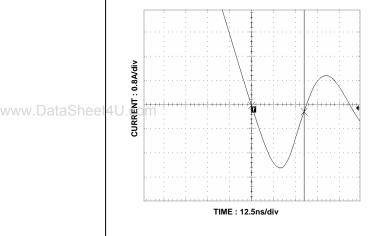


Figure 12. FDS6689S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6688).

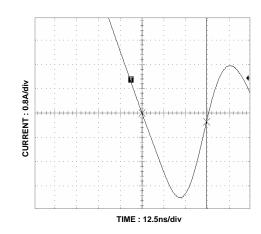


Figure 13. Non-SyncFET (FDS6688) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

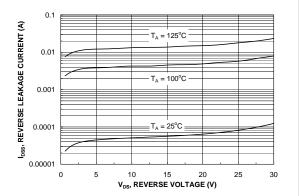


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

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Bottomless [™] FPS [™]			LittleFET™		PowerEdge™	SuperFET™				
CoolFET™	FRFET™		MICROCOL	JPLER™	PowerSaver™	SuperSOT™-				
CROSSVOLT™ GlobalOptoisolator™		isolator™			PowerTrench [®]	SuperSOT™-				
DOME™ GTO™		loolator	MicroPak™		QFET [®]	SuperSOT™.				
EcoSPARK [™] HiSeC [™]			MICROWIRE™		QS™	SyncFET™				
E ² CMOS [™]	I²C™		MSX™		QT Optoelectronics™	TinyLogic®				
EnSigna™	i-Lo™		MSXPro™		Quiet Series™	TINYOPTO™				
FACT™		nnect™	OCX™		RapidConfigure™	TruTranslatio				
FACT Quiet Seri	es™	mpliedDisconnect™ s™			RapidConnect™	UHC™				
		TM	OCXPro™ OPTOLOGIC [®]		μSerDes™	UltraFET [®]				
Across the board. Around the world.™ The Power Franchise [®] Programmable Active Droop™			OPTOPLAN	_ JAR™	SILENT SWITCHER®					
			PACMAN [™]		SMART START™	VCX™				
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